

Contents

vii *Conference Committee*

SESSION 1

- 3 **Mid- and near-infrared spectroscopy of polymers: time-resolved studies and remote sensing applications** [CR69-01]
S. Okretic, N. Völkl, H. W. Siesler, Univ. of Essen (FRG)
- 23 **Four-wave mixing: applications to fundamental research and photonics technology** [CR69-02]
P. N. Prasad, SUNY/Buffalo
- 43 **Characterization of polymers in solution with light scattering** [CR69-03]
E. H. Nordmeier, Univ. Osnabrück (FRG)
- 74 **Mössbauer spectroscopy of iron containing polymers** [CR69-05]
H. Franke, Univ. Duisburg (FRG)

SESSION 2

- 103 **UV-vis spectroscopy as an analytical tool for the characterization of polymers** [CR69-06]
G. Manivannan, Surfacine Consumer Products LLC
- 121 **Laser atomic fluorescence characterization of materials** [CR69-07]
S. B. Mirov, A. Yu. Dergachev, Univ. of Alabama/Birmingham
- 146 **Dielectric spectroscopy as an analytical technique for the characterization of polymeric solids** [CR69-09]
G. J. Pratt, Univ. of Melbourne (Australia); M. J. A. Smith, Univ. of Warwick (UK)

SESSION 3

- 175 **SEM techniques for materials characterization** [CR69-10]
J. Beauvais, D. Drouin, R. Gauvin, Univ. de Sherbrooke (Canada)
- 200 **Review of transmission electron microscopy for the characterization of materials** [CR69-11]
R. Gauvin, Univ. de Sherbrooke (Canada)
- 230 **Materials analysis using high-energy ion scattering** [CR69-12]
E. J. Knystautas, Univ. Laval (Canada)
- 251 **Characterization of optical materials using Auger electron spectroscopy** [CR69-13]
M. R. Davidson, Univ. of Toronto

Materials Characterization and Optical Properties: A Critical Review, edited by Roger A. Lessard, Hilmar Franke, Proc. of SPIE Vol. 10291 (CR 69), 1029101 · © (1997) 2017 SPIE
CCC code: 0277-786X/17/\$18 · doi: 10.1117/12.2284219

280 **Surface analysis with scanning probe microscopy [CR69-14]**
T. G. Ruskell, National Institute of Standards and Technology

SESSION 4

307 **Holographic characterization of optical materials [CR69-15]**
R. A. Lessard, Univ. Laval (Canada)

326 **Photothermal sensing techniques for thin film characterization [CR69-16]**
Z. L. Wu, Eastern Michigan Univ.

357 **Core level spectroscopy for surface analysis [CR69-18]**
F. J. Himpsel, R. Treusch, Univ. of Wisconsin/Madison; I. Jimenez, A. F. Jankowski, D. G. J. Sutherland, L. J. Terminello, Lawrence Livermore National Lab.; C. Heske, R. C. C. Perera, D. K. Shuh, W. M. Tong, J. H. Underwood, Lawrence Berkeley National Lab.; J. A. Carlisle, Virginia Commonwealth Univ.; T. A. Callcott, J. J. Jia, Univ. of Tennessee/Knoxville; D. L. Ederer, Tulane Univ.; D. M. Gruen, A. R. Krauss, D. C. Zuiker, Argonne National Lab.; G. L. Doll, Timkin Research

SESSION 5

377 **EPR and ENDOR characterization of nonlinear optical materials [CR69-19]**
L. E. Halliburton, West Virginia Univ.

398 **Ellipsometry as a characterization technique [CR69-20]**
V.-V. Truong, Univ. de Moncton (Canada); N. Le-quang, Nanoptix Inc. (Canada)

423 **SIMS characterization of optical materials [CR69-22]**
F. Caccavale, Univ. di Padova (Italy)

SESSION 6

463 **Characterization of polymeric films by integrated optics [CR69-23]**
J. D. Swalen, Univ. of California/Santa Cruz

480 **Electric-field-induced second harmonic generation [CR69-24]**
F. Kajzar, CEA-LETI (France)

501 **Z-scan technique for nonlinear materials characterization [CR69-25]**
E. W. Van Stryland, CREOL/Univ. of Central Florida; M. Sheik-Bahae, Univ. of New Mexico

525 **Characterization of polymers and particles with the analytical ultracentrifuge [CR69-26]**
H. H. Cölfen, Max Planck Institute of Colloids and Interfaces (FRG)

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- 5 **Emile J. Knystautas**, Université Laval (Canada)
- 6 **Robert A. Fisher**, RA Fisher Associates